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# HM6207H Series

256 k High Speed SRAM (256-kword × 1-bit)

# HITACHI

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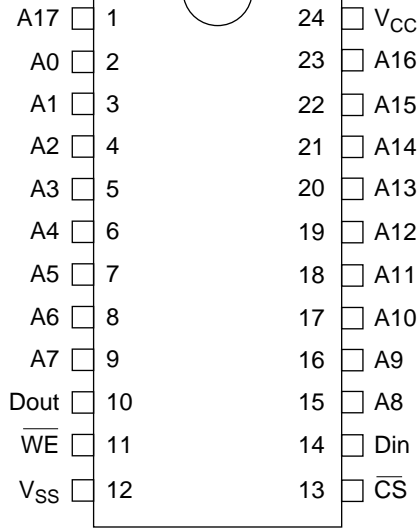
## Features

- Single 5 V supply and high density 24-pin package
- High speed  
Access time: 25/35/45 ns (max)
- Low power
  - Operation: 300 mW (typ)
  - Standby: 100  $\mu$ W (typ)  
30  $\mu$ W (typ) (L-version)
- Completely static memory required, no clock or timing strobe required
- Equal access and cycle time
- Directly TTL compatible, all inputs and outputs
- Battery backup operation capability (L-version)

## Ordering Information

Type No.	Access Time	Package
HM6207HP-25	25 ns	300-mil 24-pin plastic DIP (DP-24NC)
HM6207HP-35	35 ns	
HM6207HP-45	45 ns	
HM6207HLP-25	25 ns	300-mil 24-pin SOJ (CP-24D)
HM6207HLP-35	35 ns	
HM6207HLP-45	45 ns	
HM6207HJP-25	25 ns	300-mil 24-pin SOJ (CP-24D)
HM6207HJP-35	35 ns	
HM6207HJP-45	45 ns	
HM6207HLJP-25	25 ns	300-mil 24-pin SOJ (CP-24D)
HM6207HLJP-35	35 ns	
HM6207HLJP-45	45 ns	

## Pin Arrangement

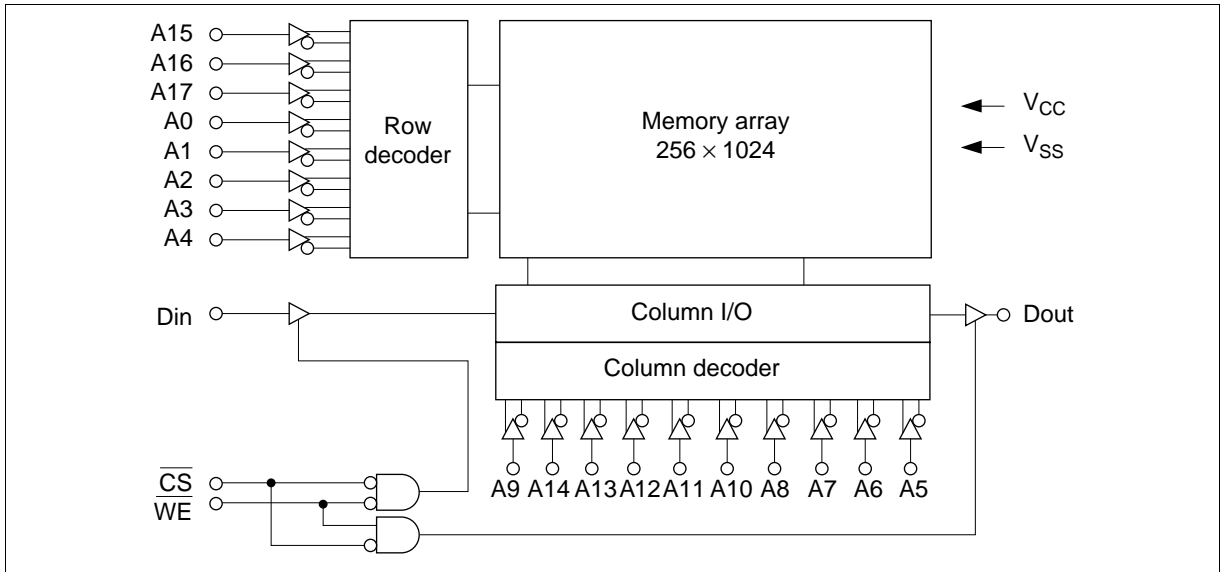


(Top view)

## Pin Description

Pin Name	Function
A0–A17	Address
Din	Data input
Dout	Data output
$\overline{CS}$	Chip select
$\overline{WE}$	Write enable
$V_{CC}$	Power supply
$V_{SS}$	Ground

**Block Diagram**



**Function Table**

$\overline{CS}$	$\overline{WE}$	Mode	$V_{CC}$ Current	I/O Pin	Ref. Cycle
H	×	Not selected	$I_{SB}, I_{SB1}$	High-Z	—
L	H	Read	$I_{CC}$	Dout	Read cycle
L	L	Write	$I_{CC}$	High-Z	Write cycle

Note: × = Don't care.

**Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Voltage on any pin relative to $V_{SS}$	$V_{in}$	-0.5 <sup>1</sup> to +7.0	V
Power dissipation	$P_T$	1.0	W
Operating temperature range	$T_{opr}$	0 to +70	°C
Storage temperature range	$T_{stg}$	-55 to +125	°C
Storage temperature range under bias	$T_{bias}$	-10 to +85	°C

Note: 1.  $V_{in\ min} = -2.5\ V$  for pulse width < 10 ns.

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## Recommended DC Operating Conditions (Ta = 0 to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	$V_{CC}$	4.5	5.0	5.5	V
	$V_{SS}$	0	0	0	V
Input high (logic 1) voltage	$V_{IH}$	2.2	—	6.0	V
Input low (logic 0) voltage	$V_{IL}$	-0.5 <sup>†</sup>	—	0.8	V

Note: 1.  $V_{IL}$  min = -2.0 V for pulse width ≤ 10 ns.

## DC Characteristics (Ta = 0 to +70°C, $V_{CC} = 5\text{ V} \pm 10\%$ , $V_{SS} = 0\text{ V}$ )

Parameter	Symbol	HM6207H-25		HM6207H-35/45		Unit	Test Conditions	
		Min	Typ <sup>†</sup>	Min	Typ <sup>†</sup>			
Input leakage current	$I_{LI}$	—	—	2.0	—	2.0	$\mu\text{A}$ $V_{CC} = \text{Max}$ , $V_{in} = V_{SS}$ to $V_{CC}$	
Output leakage current	$I_{LO}$	—	—	10.0	—	10.0	$\mu\text{A}$ $\overline{CS} = V_{IH}$ , $V_{I/O} = V_{SS}$ to $V_{CC}$	
Operating power supply current	$I_{CC}$	—	60	120	—	50	100	$\text{mA}$ $\overline{CS} = V_{IL}$ , $I_{I/O} = 0\text{ mA}$ , min cycle, duty = 100%
	$I_{CC1}$	—	40	80	—	40	80	$\text{mA}$ $\overline{CS} = V_{IL}$ , $I_{I/O} = 0\text{ mA}$ , t cycle = 50 ns, duty = 100%
Standby power supply current	$I_{SB}$	—	20	40	—	15	30	$\text{mA}$ $\overline{CS} = V_{IH}$ , min cycle
Standby power supply current (1)	$I_{SB1}$	—	0.02	2.0	—	0.02	2.0	$\text{mA}$ $\overline{CS} \geq V_{CC} - 0.2\text{ V}$ , $0\text{ V} \leq V_{in} < 0.2$ , or $V_{in} \geq V_{CC} - 0.2\text{ V}$
	L- Version	—	0.006	0.1	—	0.006	0.1	
Output low voltage	$V_{OL}$	—	—	0.4	—	—	0.4	V $I_{OL} = 8\text{ mA}$
Output high voltage	$V_{OH}$	2.4	—	—	2.4	—	—	V $I_{OH} = -4.0\text{ mA}$

Note: 1. Typical values are at  $V_{CC} = 5.0\text{ V}$ ,  $T_a = +25^\circ\text{C}$  and not guaranteed.

## Capacitance (Ta = 25°C, f = 1 MHz)<sup>\*1</sup>

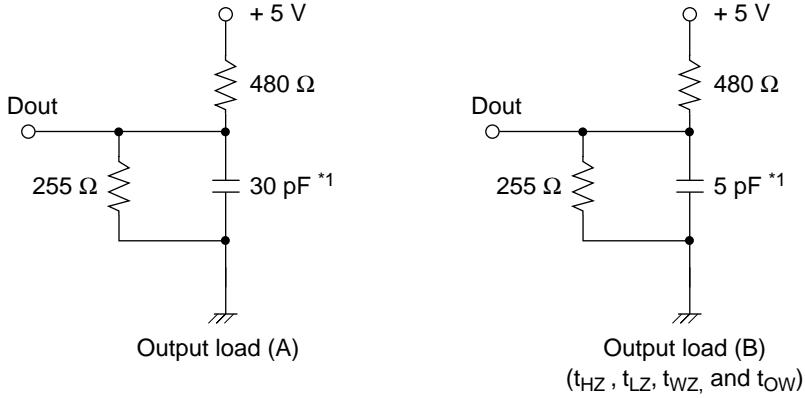
Parameter	Symbol	Min	Max	Unit	Test Conditions
Input capacitance	$C_{in}$	—	6	pF	$V_{in} = 0\text{ V}$
Output capacitance	$C_{out}$	—	10	pF	$V_{out} = 0\text{ V}$

Note: 1. This parameter is sampled and is not 100% tested.

**AC Characteristics** ( $T_a = 0$  to  $+70^\circ\text{C}$ ,  $V_{CC} = 5\text{ V} \pm 10\%$  unless otherwise noted)

**Test Conditions**

- Input pulse levels:  $V_{SS}$  to 3.0 V
- Input and output timing reference levels: 1.5 V
- Input rise and fall time: 5 ns
- Output load: See figures



Note: 1. Including scope and jig

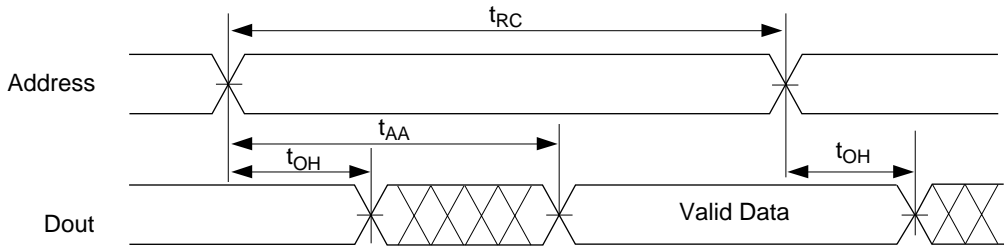
**Read Cycle**

Parameter	Symbol	HM6207H-25		HM6207H-35		HM6207H-45		Unit
		Min	Max	Min	Max	Min	Max	
Read cycle time	$t_{RC}$	25	—	35	—	45	—	ns
Address access time	$t_{AA}$	—	25	—	35	—	45	ns
Chip select access time	$t_{ACS}$	—	25	—	35	—	45	ns
Output hold from address change	$t_{OH}$	5	—	5	—	5	—	ns
Chip selection to output in low-Z	$t_{LZ}^{-1}$	5	—	5	—	5	—	ns
Chip deselection to output in high-Z	$t_{HZ}^{-1}$	0	15	0	20	0	20	ns

Note: 1. Transition is measured  $\pm 200$  mV from steady-state voltage with Load (B).

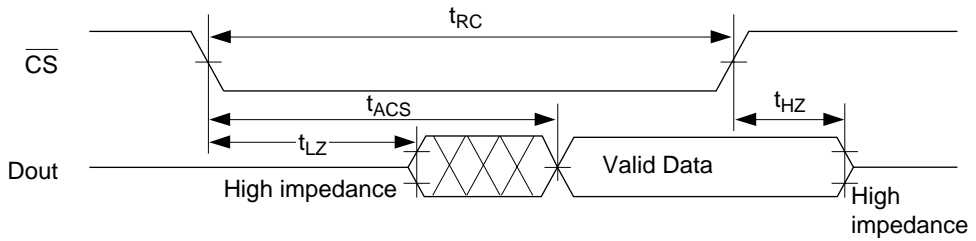
These parameters are sampled and not 100% tested.

## Read Timing Waveform (1)



- Notes: 1.  $\overline{WE}$  is high for read cycle.  
2. Device is continuously selected,  $\overline{CS} = V_{IL}$ .

## Read Timing Waveform (2)



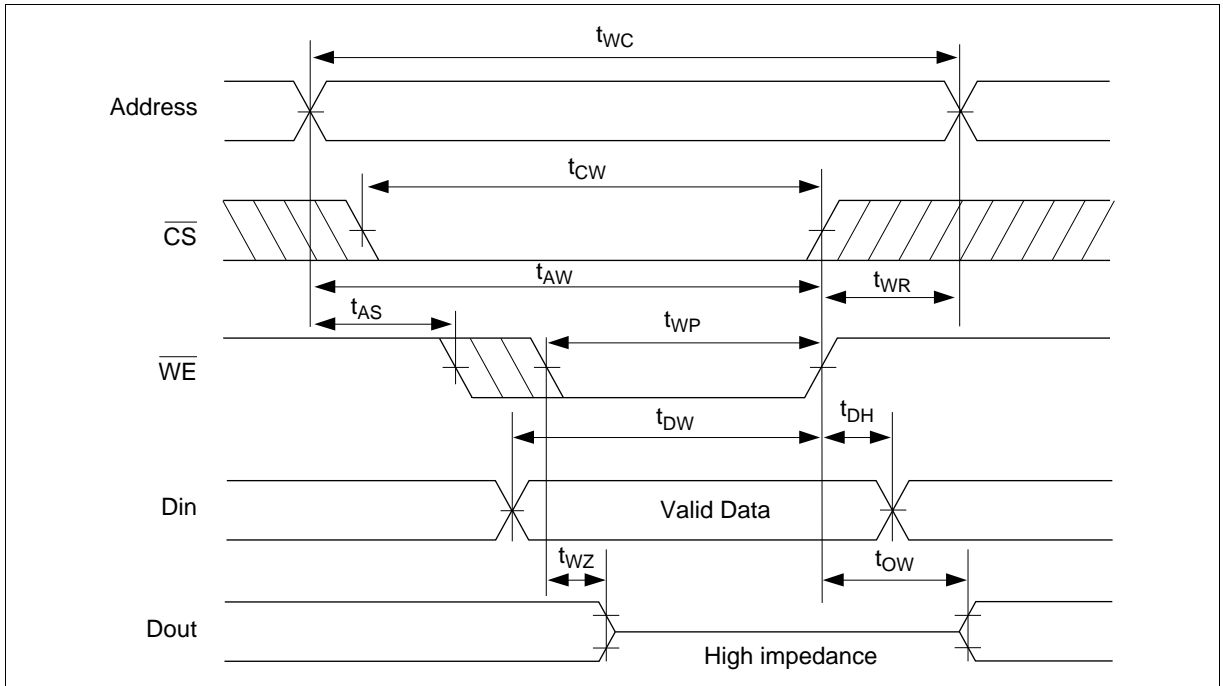
- Notes: 1.  $\overline{WE}$  is high for read cycle.  
2. Address valid prior to coincident with  $\overline{CS}$  transition low.

Write Cycle

Parameter	Symbol	HM6207H-25		HM6207H-35		HM6207H-45		Unit
		Min	Max	Min	Max	Min	Max	
Write cycle time	$t_{WC}$	25	—	35	—	45	—	ns
Chip selection to end of write	$t_{CW}$	20	—	30	—	40	—	ns
Address valid to end of write	$t_{AW}$	20	—	30	—	40	—	ns
Address setup time	$t_{AS}$	0	—	0	—	0	—	ns
Write pulse width	$t_{WP}$	20	—	25	—	25	—	ns
Write recovery time	$t_{WR}$	3	—	3	—	3	—	ns
Data valid to end of write	$t_{DW}$	15	—	20	—	20	—	ns
Data hold time	$t_{DH}$	0	—	0	—	0	—	ns
Write enabled to output in high-Z	$t_{WZ}^{*1}$	0	15	0	20	0	25	ns
Output active from end of write	$t_{OW}^{*1}$	0	—	0	—	0	—	ns

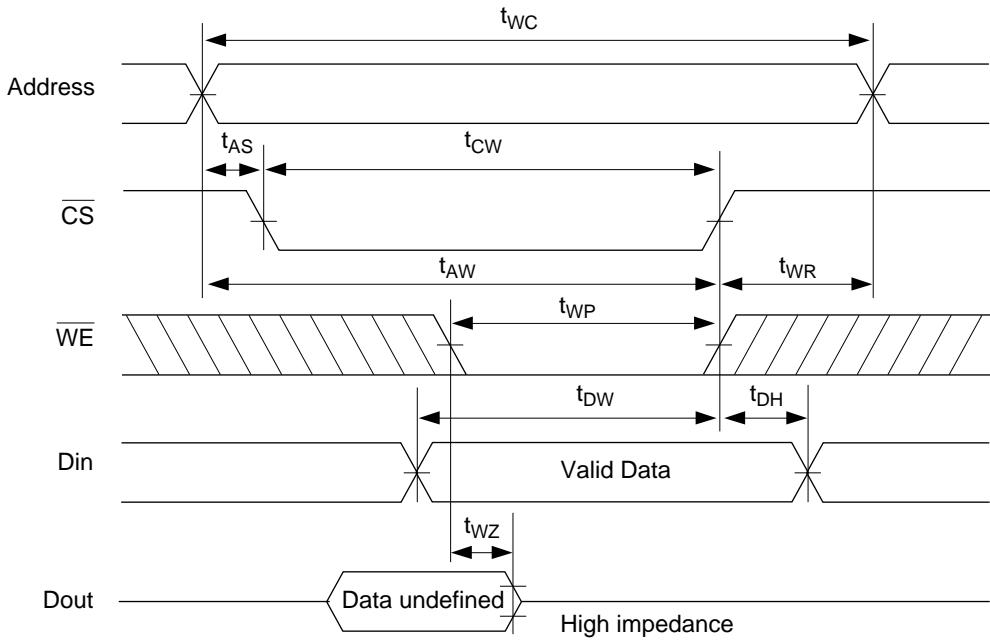
Note: 1. Transition is measured  $\pm 200$  mV from high-impedance voltage with Load (B).  
 This parameter is sampled and is not 100% tested.

Write Timing Waveform (1) ( $\overline{WE}$  Controlled)



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## Write Timing Waveform (2) ( $\overline{CE}$ Controlled)



- Notes:
1. A write occurs during the overlap of a low  $\overline{CS}$  and a low  $\overline{WE}$ .
  2.  $t_{WR}$  is measured from the earlier of  $\overline{CS}$  or  $\overline{WE}$  going high to the end of the write cycle.
  3. If the  $\overline{CS}$  low transition occurs simultaneously with the  $\overline{WE}$  low transition, the output buffers remain in a high impedance state.
  4.  $D_{out}$  has the same phase as write data in this write cycle, if  $t_{WR}$  is long enough.



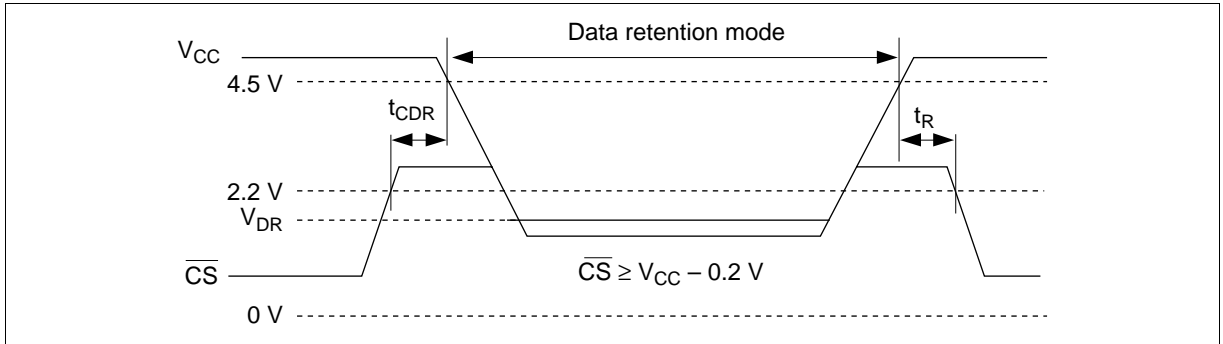
**Low  $V_{CC}$  Data Retention Characteristics** ( $T_a = 0$  to  $+70^\circ\text{C}$ )

These characteristics are guaranteed for the L-version only.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
$V_{CC}$ for data retention	$V_{DR}$	2.0	—	—	V	$\overline{CS} \geq V_{CC} - 0.2\text{ V}$ , $V_{in} \geq V_{CC} - 0.2\text{ V}$ , or $0\text{ V} \leq V_{in} \leq 0.2\text{ V}$
Data retention current	$I_{CCDR}$	—	2	$50^{-1}$	$\mu\text{A}$	
Chip deselect to data retention time	$t_{CDR}$	0	—	—	ns	
Operation recovery time	$t_R$	5	—	—	ms	

Note: 1.  $V_{CC} = 3.0\text{ V}$

**Low  $V_{CC}$  Data Retention Timing Waveform**

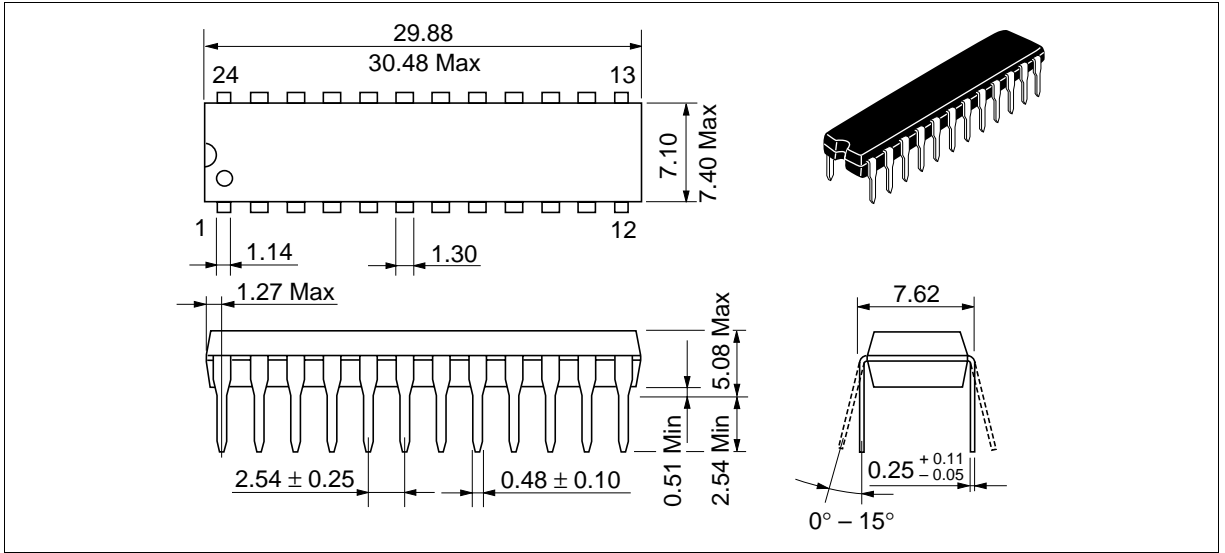


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## Package Dimensions

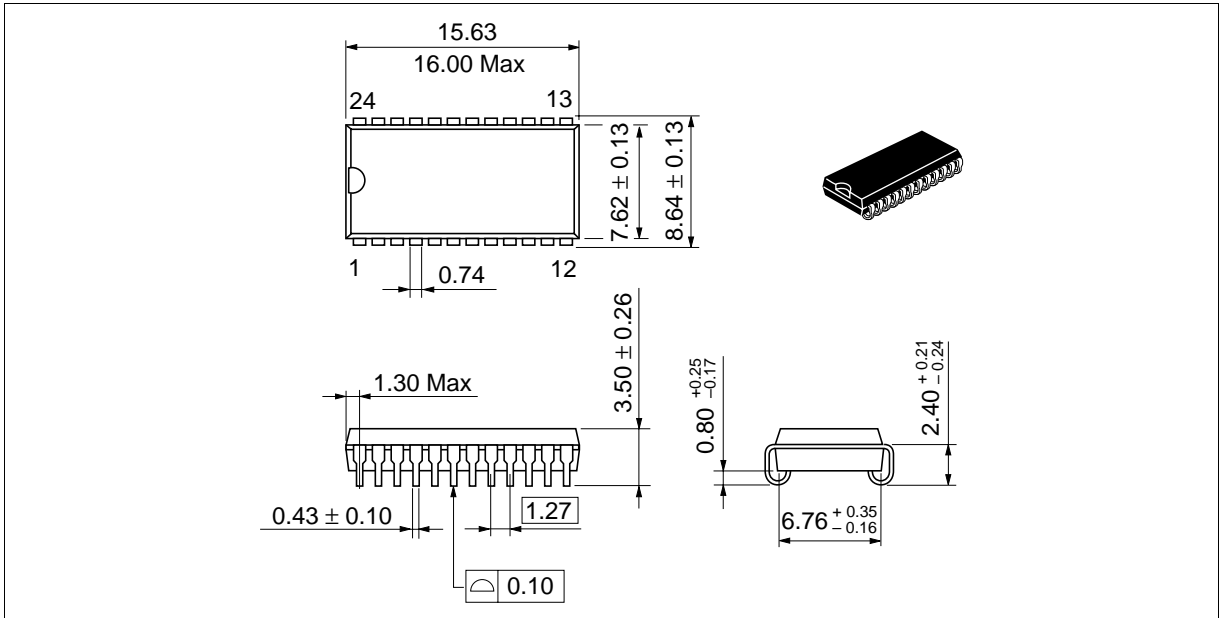
HM6207HP/HLP Series (DP-24NC)

Unit: mm



HM6207HJP/HLJP Series (CP-24D)

Unit: mm



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# HITACHI

## Hitachi, Ltd.

Semiconductor & IC Div.

Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100, Japan

Tel: Tokyo (03) 3270-2111

Fax: (03) 3270-5109

### For further information write to:

Hitachi America, Ltd.

Semiconductor & IC Div.

2000 Sierra Point Parkway

Brisbane, CA. 94005-1835

U S A

Tel: 415-589-8300

Fax: 415-583-4207

Hitachi Europe GmbH

Electronic Components Group

Continental Europe

Dornacher Straße 3

D-85622 Feldkirchen

München

Tel: 089-9 91 80-0

Fax: 089-9 29 30 00

Hitachi Europe Ltd.

Electronic Components Div.

Northern Europe Headquarters

Whitebrook Park

Lower Cookham Road

Maidenhead

Berkshire SL6 8YA

United Kingdom

Tel: 0628-585000

Fax: 0628-778322

Hitachi Asia Pte. Ltd.

16 Collyer Quay #20-00

Hitachi Tower

Singapore 0104

Tel: 535-2100

Fax: 535-1533

Hitachi Asia (Hong Kong) Ltd.

Unit 706, North Tower,

World Finance Centre,

Harbour City, Canton Road

Tsim Sha Tsui, Kowloon

Hong Kong

Tel: 27359218

Fax: 27306071